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Ipposhi, T.; Maegawa, S.; Inoue, Y.;
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Idei, Y.; Homma, N.; Nambu, H.; Sakurai, Y.;
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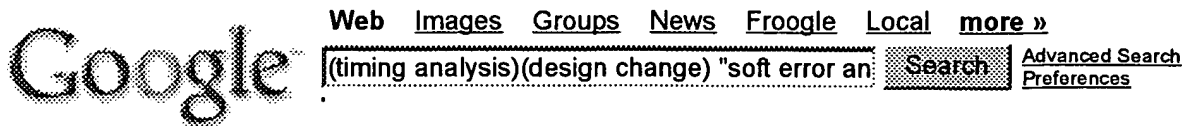
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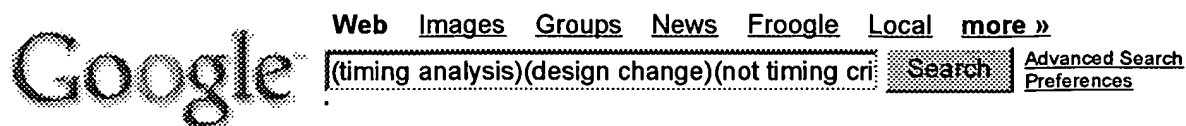
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